

EVA100 ATPG Tools

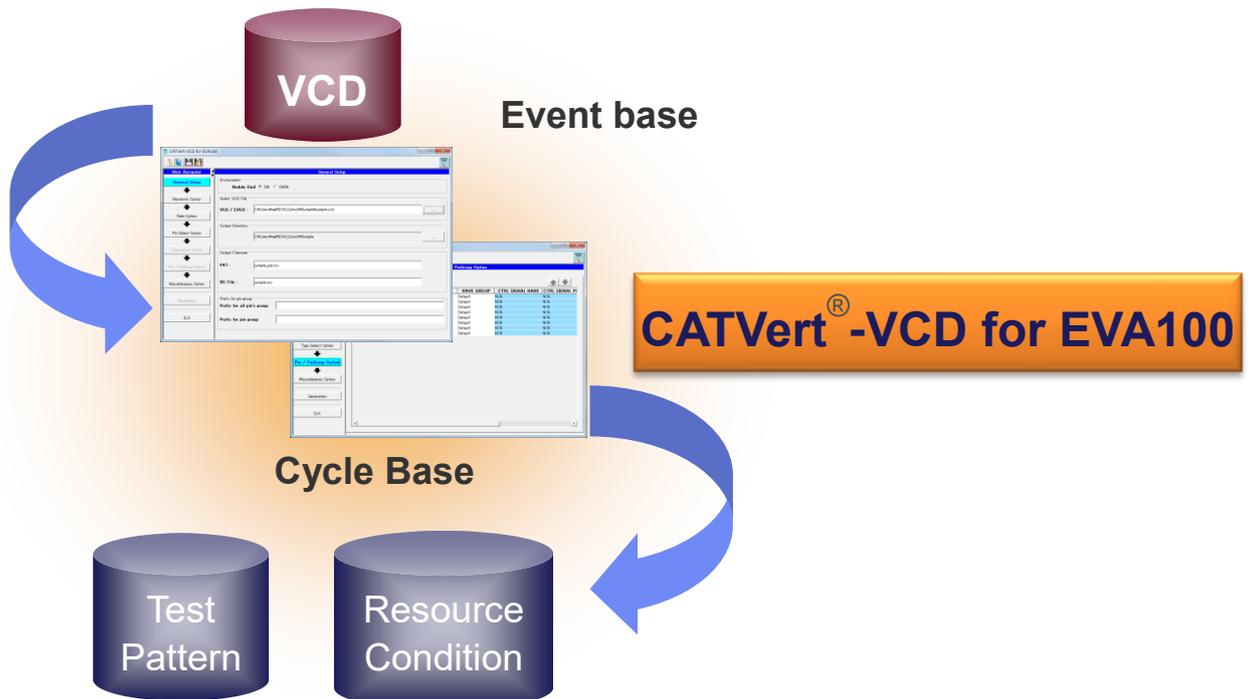
Measurement System EVA100

- **STIL - STIL IEEE® Std 1450.0-1999**
- **WGL - Waveform Generation Language**



ATPG Pattern Conversion Software

- **VCD Value Change Dump / EVCD Extended VCD (IEEE® Std 1364-2005)**



■ Features

■ Conversion GUI

The Simple GUI for pattern conversion is available. It is very easy to use and is able to generate the conversion option files for pattern conversion which are listed in below.

■ Conversion option files

Pin map definition file - This definition file is to use the pins targeted for conversion, conversion conditions for each pin, and sequence of patterns to be output are defined in the pin map definition file.

Pin group definition file - This definition file is to define the pin groups and pins which are members of the pin groups are defined in the pin group definition file.

Option definition file - This file is to define the options during the conversion. For VCD Measurement periods, start and stop time of conversion, and how to handle events are defined in the option definition file. For STIL/WGL this definition file allows users to replace events described in the STIL file or set input signal WFCs described in the STIL file for the entire STIL file to be converted.

■ Support pattern conversion command

Support the command line for pattern conversion once you create the option files, user can convert multiple ATPG patterns by using command line or batch file.

■ Hardware Restriction Check

STILReader and CATVert®-VCD has the hardware restriction check functions. For instance Max/Min Rate, pin count and IO dead-band etc.

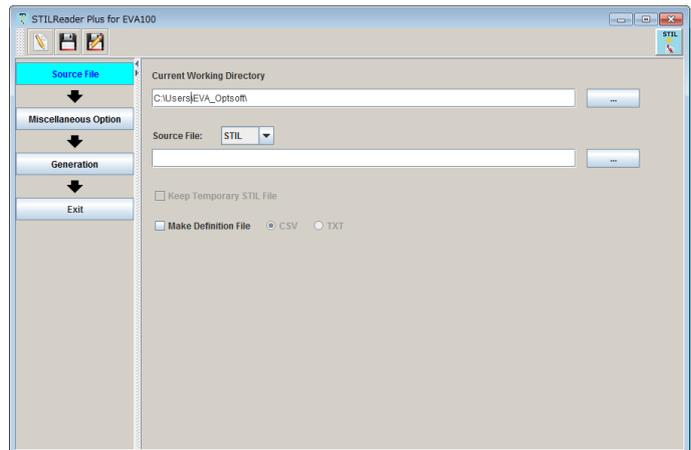


Figure 1 Conversion GUI

	STILReader Plus for EVA100	CATVert®-VCD for EVA100
Operating system	Windows7 / Windows10	Windows7 / Windows10
ATPG File format	STIL IEEE® Std 1450.0-1999 IEEE® Std 1450.1-2005 WGL Waveform Generation Language	VCD (Value Change Dump) EVCD (Extended VCD (IEEE® Std 1364-2005))
Supported Modules	DM/DM64	DM/DM64
Generation Import file	Yes	Yes
License scheme	ATFLEX/Network/Annual	ATFLEX/Network/Annual

Table 1 Specification

Trademarks and Registered Trademarks

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